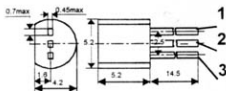


# ML 406

Silicon controlled rectifier (SCR)  
in TO-92 package



Pinouts:

1- Anode, 2- Gate, 3- Cathode

## Maximum ratings

Symbol	Parameter, units	Limits
$V_{drm}$	Peak repetitive forward voltage, V, $R_{gk}=1k\Omega$	400
$V_{rrm}$	Repetitive peak reverse voltage, V	6
$I_{t(rms)}$	On-state current, A All Conduction Angles	0.8
$I_t(A_V)$	Average on-state current, A Half Cycle, $\theta=180^\circ$	0.5
$I_{t(sm)}$	Nonrepetition on-state current, A Half Cycle, 50Hz	7.0
$V_{grm}$	Peak reverse gate voltage, V $I_{gr}=0.01mA$	6.0

## Electrical characteristics ( $T_A = 25^\circ C$ )

Symbol	Parameter, units test conditions	Limits	
		min	max
$I_{drm}$	Off state leakage current, $\mu A$ , @ $V_{drm}$ , $R_{gk}=1k\Omega$		1
$V_t$	On state voltage, V, $I_t=1.2A$		1.93
$I_{gt}$	Gate trigger current, mA, $V_g=6V$		0.12
$V_{gt}$	Gate trigger voltage, V, $I_g=6V$		0.8
$I_h$	Holding current, mA, $R_{gk}=1k\Omega$		5
$dV/dt$	Crit. rate of voltage rise, V/ $\mu s$ , $V_g=0.67V_{drm}$ , $R_{gk}=1k\Omega$	25	
$dI/dt$	Crit. rate of current rise, A/ $\mu s$ , $I_g=10mA$ , $dI_g/dt=0.1A/\mu s$	30	
$t_{gd}$	Gate control delay time, ns, $I_g=10mA$ , $dI_g/dt=0.1A/\mu s$		200